

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 06618-457001	Application No. 09/576,654
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR § 1.98(b))		Applicant Daniel P. Weitekamp	
		Filing Date May 22, 2000	Group Art Unit 2856 2878

U.S. Patent Documents							
Examiner Initial	Desig. ID	Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
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	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
TXL	AQ	Rugar et al., "Improved fiber-optic interferometer for atomic force microscopy," <i>Applied Physics Letters</i> . Vol. 55, pp. 2588-2590, 18 December 1989.
TXL	AR	Walters et al., "Elastic strain of freely suspended single-wall carbonnanotube ropes," <i>Applied Physics Letters</i> . Vol. 74, pp. 3803-3805, 21 June 1999.
TXL	AS	Leskowitz et al., "Observation of Force-Detected Nuclear Magnetic Resonance in a Homogenous Magnetic Field," <i>Bulletin of the American Physical Society</i> , Vol. 44, pp. 543, (1999).
	AT	

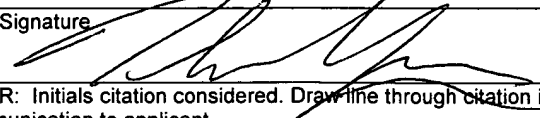
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
TXL	AA	4,982,088	Jan. 1, 1991	Weitekamp et al.	250	291	
	AB						
	AC						
	AD						
	AE						

Foreign Patent Documents or Published Foreign Patent Applications								
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	AG							
	AH							
	AI							

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Examiner Initial	Desig. ID	Document
TXL	AJ	Nie et al., "Probing Single Molecules and Single Nanoparticles by Surface-Enhanced Raman Scattering," Science, Vol. 275, pp. 1102-1106, February 21, 1997
TXL	AK	Michaels et al., "Surface Enhanced Raman Spectroscopy of Individual Rhodamine 6G Molecules on Large Ag Nanocrystals," Journal of the American Chemical Society, Vol. 121, No. 43, pp. 9932-9939, November 3, 1999
TXL	AL	Gordon et al., "Motion of atoms in a radiation trap," Physical Review A, Vol. 21, No. 5, pp. 1606-1617, May 1980
TXL	AM	Novotny et al., "Theory of Nanometric Optical Tweezers," Physical Review Letters, Vol. 79, No. 4, pp. 645-648, July 28, 1997
TXL	AN	Ashkin, "Forces of a Single-Beam Gradient Laser Trap on a Dielectric Sphere in the Ray Optics Regime," Methods in Cell Biology, Vol. 55, pp. 1-27, 1998
TXL	AO	Pizarro et al., "Magnetic Resonance of Trapped Ions by Spin-Dependent Cyclotron Acceleration," Bulletin of Magnetic Resonance, Vol. 14, No. 1-4, pp. 220-223, 1992
TXL	AP	Sidles, "Noninductive detection of single-proton magnetic resonance," Applied Physics Letters, Vol. 58, No. 24, pp. 2854-2856, June 17, 1991
TXL	AQ	Sidles et al., "Magnetic resonance force microscopy," Reviews of Modern Physics, Vol. 67, No. 1, pp. 249-265, January 1995
TXL	AR	Leskowitz et al., "Force-detected magnetic resonance without field gradients," Solid State Nuclear Magnetic Resonance, Vol. 11, pp. 73-86, 1998

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